Search Notes

Application/Control		Applicant(s)/Patent under Reexamination TERADA, TOMOYASU	
10/564,955	TERADA, TO		
Examiner	Art Unit		
Jinhee J. Lee	2831		

SEARCHED					
Class	Subclass	Date	Examiner		
174	72a	9/2/2006	LEE		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
174	as above	9/2/2006	LEE		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
See text search attached	9/2/2006	LEE		